

## CLAIMS

What is Claimed is:

1. A conductor-pattern testing method for inspecting an electrode substrate having a conductor pattern constituted by a plurality of elongated conductors formed in parallel to each other on a base and further having a dummy pattern constituted by a plurality of dummy conductors formed in an area on said base where said conductor pattern is not formed, said method examining electrical characteristics among said plurality of conductors by establishing the contact of at least two probes having a positional relationship defined so that the two probes are brought into contact with at least two conductors among said plurality of conductors,

wherein said plurality of dummy conductors disposed in the array direction of said plurality of conductors to constitute said dummy pattern are formed in segments so as to prevent two or more of the probes from being simultaneously in contact with any one of said plurality of dummy conductors and said at least two probes are progressively moved for inspection in the array direction of said plurality of conductors.

2. A conductor-pattern testing method according to Claim 1, wherein said plurality of conductors are electrodes or wiring lines formed on said base.

3. A conductor-pattern testing method according to Claim 1, wherein said dummy conductors disposed in the array direction of said plurality of electrodes to constitute said dummy pattern are mutually set apart between any pair of  
5 said at least two probes in the extending direction of said plurality of electrodes.

4. A conductor-pattern testing method according to Claim 1, wherein each of said plurality of dummy conductors disposed in the array direction of said plurality of conductors to constitute said dummy pattern is shorter when  
5 viewed along the extending direction of said plurality of conductors than the minimum length between any pair of said at least two probes in the extending direction of said plurality of conductors.

5. A conductor-pattern testing method according to Claim 1, wherein said plurality of dummy conductors disposed in the array direction of said plurality of conductors to constitute said dummy pattern are mutually separated in the  
5 array direction of said plurality of conductors.

6. A conductor-pattern testing method according to Claim 1, wherein said base is a substrate, and said electrode substrate is an electro-optical device in which a plurality of electrodes and wiring lines are formed in a particular pattern on the surface of said substrate and electro-optical material to be affected by an electric field generated by said plurality of electrodes are further disposed thereover.

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7. An electro-optical device having a conductor pattern constituted by a plurality of elongated conductors formed in parallel to each other on a base, further having a dummy pattern constituted by a plurality of dummy conductors formed in an area on said base where said conductor pattern is not formed, and in which electro-optical material is disposed on said conductor pattern, wherein said plurality of dummy conductors disposed in the array direction of said plurality of conductors to constitute said dummy pattern are mutually separated in the extending direction of said plurality of conductors.

8. An electro-optical device having a conductor pattern constituted by a plurality of elongated conductors formed in parallel to each other on a base, further having a dummy pattern constituted by a plurality of dummy conductors formed in an area on said base where said conductor pattern is not formed, and in which electro-optical material is disposed on said conductor pattern, wherein said plurality of dummy conductors disposed in the array direction of said plurality of conductors to constitute said dummy pattern are mutually separated in the array direction of said plurality of conductors.

9. An electro-optical device according to Claim 8,  
wherein said plurality of dummy conductors disposed in the  
array direction of said plurality of conductors to  
constitute said dummy pattern are mutually separated in the  
5 extending direction of said plurality of conductors.

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